

CONFERENCE FEES

| | Delegate Fee | Life Lectures | Conference Dinners (6th & 7th Sept 05) | Accommodation | Total (inc VAT) |
|---|--------------|---------------|--|--------------------------|-----------------|
| Delegate Presenting a Paper/IEE Member (3 Days) | £320.00 | £60.00 | £45.00 | £60.00 (3 Nights at £20) | £570.00 |
| Delegate not Presenting a Paper | £335.00 | £60.00 | £45.00 | £60.00 (3 Nights at £20) | £588.00 |
| Student Delegate (3 days) | £280.00 | £60.00 | £45.00 | £60.00 (3 Nights at £20) | £523.00 |
| Delegate not Presenting a Paper (1 day) | £175.00 | £60.00 | £30.00 (1 dinner) | £20.00 (1 Night at £20) | £335.00 |

The above charges explained:

Conference Dinners includes the formal evening dinners on the 6th and 7th September 2005 (transport to dinners will be provided from Storthes Hall Student Village).

Accommodation – Storthes Hall Student Village will be the main conference accommodation. Situated in 366 acres of attractive parkland to the south of the town it offers bedrooms, all with en suite toilet, washbasin and shower. This is bed and full English breakfast accommodation at a specially negotiated price of £20 per person per night.

7th ISMTII 2005

Conference Announcement

Call for Papers

Conference Committee:**LOCAL ORGANISING COMMITTEE**

Conference Chair Prof. Xiangqian (Jane) Jiang (University of Huddersfield)
 Prof. Liam Blunt (University of Huddersfield) Programme
 Prof. Paul Scott (Taylor Hobson Limited) Poster Session
 Secretary Mrs. Liz Rees (University of Huddersfield)

INTERNATIONAL PROGRAMME COMMITTEE

Chair Dr. Seton Bennett (National Physical Laboratory, UK)
 Prof. Zhu Li (Huazhong University of Science and Technology, China)
 Prof. Maurice Cox (National Physical Laboratory, UK)
 Dr. Xianping Liu (The University of Warwick, UK)
 Prof. Volker Hans (University of Duisburg-Essen, Germany)
 Prof. Bengt-Goran Rosen (Halmstad University, Sweden)
 Prof. Ryszard Jablonski (Warsaw University of Technology, Poland)
 Dr. Sarwat Zahwi (National Institute for Standards, Egypt)
 Prof. Yuri Chugui (Technological Design Institute of Scientific Instrument Engineering, Russia)
 Mr. Jim Bryan (USA)
 Prof. Chunyong Yin (Tsinghua University, China)

INTERNATIONAL SCIENTIFIC COMMITTEE:

Chair Prof. David J. Whitehouse (University of Warwick, UK)
 Dr. Richard Leach (National Physical Laboratory, UK)
 Prof. Albert Weckenmann (Friedrich-Alexander University-Erlangen – Nuremberg, Germany)
 Prof. Derek Chetwynd (University of Warwick, UK)
 Dr. Michael Krystek (Physikalisch-Technische Bundesanstalt, Germany)
 Dr. Chang Hsu (Centre for Measurement Standards, Taiwan, China)
 Dr. Trevor Eward (National Physical Laboratory, UK)
 Prof. JiubinTan (Harbin Institute of Technology, China)
 Prof. Kuangchao Fan (National Taiwan University, Taiwan, China)

(cont'd)

Dr. Tomizo Kurosawa (National Metrology Institute, Japan)
 Dr. Victor Bykov (Nanotechnology MDT and Nanotechnology Instruments Co. Russia)
 Dr. George J. Stein (Slovak Academy of Sciences, Slovak)
 Prof. Jay Raja (University of North Carolina at Charlotte, USA)
 Prof. Don Lucco (Oklahoma State University, USA)
 Prof. Yetai Fei (Hefei University, China)
 Prof. Yongsheng Gao (Hong Kong University of Science and Technology, Hong Kong, China)
 Dr. Wei Gao (Tohoku University, Japan)
 Dr. Han Haitjema (Eindhoven University of Technology, The Netherlands)

Conference Secretariat

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7th International Symposium on
 Measurement Technology and
 Intelligent Instruments

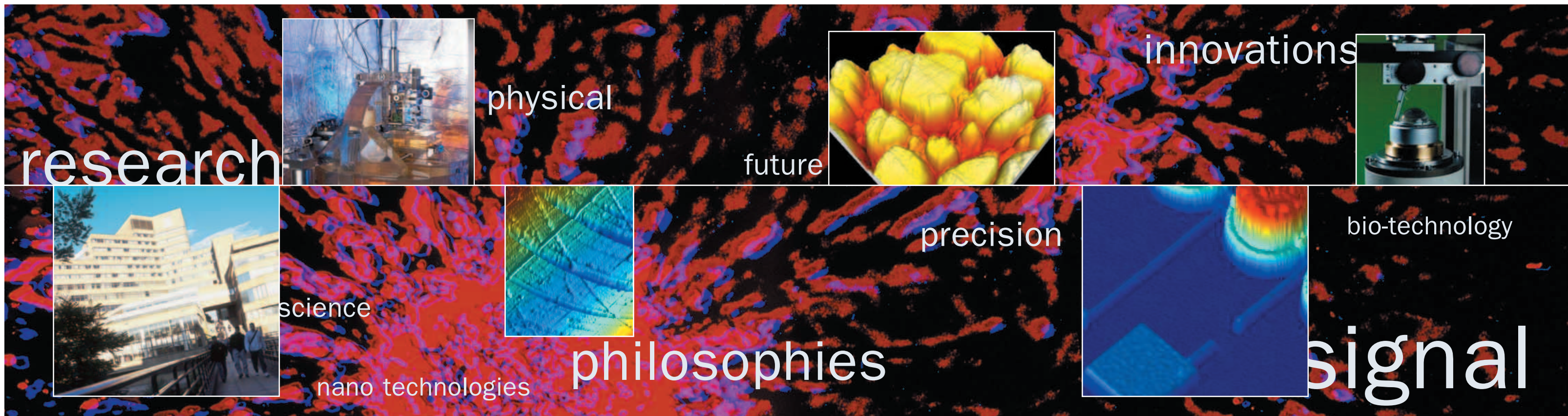
6–8 September 2005

Associated Seminar on History and
 Future Prospects in the Field of
 Measurement and Instrumentation

5 September 2005

**Centre for Precision Technologies,
 University of Huddersfield, UK**

7th International Symposium on Measurement Technology and Intelligent Instruments



Organised by



Centre for Precision Technologies, University of Huddersfield, UK

In co-operation with



National Physical Laboratory, UK



The University of Warwick, UK



Huazhong University of Science and Technology (HUST), China



International Committee on Measurements and Instrumentation (ICMI)



National Natural Science Foundation of China (NSFC)

SCOPE

The Seventh International Symposium on Measurement Technology and Intelligent Instruments (ISMTII 2005) will focus on the progress in measurement technology and intelligent instruments and their applications. The conference aims to provide an international forum for academics, professionals and engineers from different disciplines to meet and exchange their ideas, results and latest research.

Scientific Themes

- > Surface, Micro and Nano Metrology
- > Sensors, Intelligent Instruments, and Signal Processing
- > Measurement and Instrumentation
- > Uncertainty, Traceability, and Calibration
- > Software for Instruments
- > In-process and on-line Metrology
- > Applications of Sensors and Metrology (including Biotechnology)
- > Metrology for Materials Science
- > Optical Metrology and Image Processing

Plenary Lectures

Critical reviews of advanced measurement techniques and instrumentation will be provided.

Language

The language of the conference will be English.

Exhibition

There will be an exhibition covering the main themes of the conference. It will provide an excellent opportunity to promote products and services to an international gathering of professional engineers, scientists, technologists, and educationalists. Contact the Local Organising Committee for further information.

Sponsorship

A large number of delegates are expected to attend ISMTII 2005, which will therefore provide an excellent opportunity for sponsors to support the events. Contact the Local Organising Committee for further information if your organisation is interested in sponsorship opportunities.

SEMINAR SESSION

History and Future Prospects in the Field of Measurement and Instrumentation

Three world-renowned experts, who have had significant influence on measurement and instrument technologies, will give their "life lectures". All of whom have already received Life Achievement Awards in precision engineering and nanotechnology. The intention of this session is to create a unique opportunity to meet and listen to some of the world's top researchers in the field of precision metrology, sensors and instrumentation talking about the development, present state and future trends in their areas of expertise. Following the presentations an extended interaction time will allow attendees to benefit from the speakers' experiences and views. This seminar provides an unparalleled opportunity not only for students and young researchers, but also teachers, academics and industrialists to learn from these experts, thus improving their research skills and philosophy and helping to direct their views on the subjects covered.

The three speakers:

Professor David Whitehouse has had a long and distinguished career in industry and academia as a designer of surface and dimensional metrology instruments. He has written five books on the subjects, including the definitive *Handbook of surface metrology*. He also has over 200 papers and 20 patents in his name. David is often referred to as the "Father of Digital Metrology". He is a life member of the American Society of Precision Engineers, an Honorary Member of the Japanese Institution of Precision Engineers, a Fellow of the UK Institute of Physics, a Fellow of the Institute of Electrical Engineers, a Fellow of the Institute of Production Engineers, and a Senior Member of the Chinese Society of Mechanical Engineers. He has been an active member of CIRP since 1974. He has received

many honours throughout the world.

Jim Bryan is universally well known for his fundamental and wide-ranging contributions to advances in modern precision engineering in the last forty years. As one of the founding fathers of modern precision engineering, Jim has continued to make outstanding contributions to its scientific and technological development, and growth. In his tireless promotion of precision metrology, philosophies, principles, innovations, practices and standards through research, design and teaching, he has justly earned worldwide respect, admiration and friendship. He is a Chartered Fellow of the Society of Manufacturing Engineers; he has been a full member of CIRP (International Institute for Production Engineering Research) since 1964, as Secretary, Vice-President and President of the Metrology section. He was awarded the SME Research Medal by the Society of Manufacturing Engineers in 1977. He is one of six "Heroes of the Year 2000 in U.S. Manufacturing" selected by Fortune Magazine.

Dr. Erwin Loewen spent a long professional career in the field well before it acquired the name precision engineering. Working in both industry and academia he specialised in the production of diffraction gratings, some of whose tolerances need to be in the nanometer domain over significant areas. This is well before the word became so famous. Problems that had to be overcome make fascinating stories, both technical and personal. He is co-author of one of the few texts on the technology and history of the field. He is a life member of ASME, Fellow of Society of Precision Engineers, Society of Manufacturing Engineers and the Optical Society of America. He has been a member of CIRP (International Society of Production Engineering Research) serving various terms in its metrology subcommittee. For 19 years he was Chair of ASME Standards Committee B-89 on Dimensional Metrology.

CALL FOR PAPERS

Papers related to measurement technology and intelligent instruments are invited for oral or poster presentation at ISMTII 2005.

Oral Presentations

Authors are invited to submit no later than 12 November 2004 a one-page abstract in Word doc format font size 12, by post or using the ISMTII 2005 online submission form at <http://ismtii.hud.ac.uk/>.

Review and Publication

All papers will be peer-reviewed before final acceptance for publication in the Proceedings. The Proceedings will be published in the **Journal of Physics: Conference Series** by the Institute of Physics, London (EI and INSPEC included). A selected number of papers will be published as a special issue of the International Journal **Measurement Science and Technology** (SCI included).

Poster Presentations

Submissions are invited for posters on the key conference topics. One-page abstracts in Word doc format font size 12, should be submitted no later than 28 January 2005 by post or using the ISMTII 2005 online submission form on the internet site <http://ismtii.hud.ac.uk/>.

The posters provide an opportunity for authors to communicate their latest research results or to pose existing problems to solicit inputs. A selected number of the posters will be published in the **Journal of Physics: Conference Series** after peer-review. An award will be given for the best poster presentation.

All abstracts will be reviewed and acceptability communicated by 14 January 2005 for Oral Presentations and by 28 February 2005 for Poster Presentations.

Important Deadlines

- **12 November 2004**
Submission of abstracts for Oral Presentation Papers
- **14 January 2005**
Invitation to submit Oral Presentation Papers
- **20 May 2005**
Submission of manuscripts of Oral Presentation Papers
- **28 January 2005**
Submission of abstracts for Posters
- **28 February 2005**
Notification of acceptance of Posters
- **20 May 2005**
Submission of manuscripts for Poster Papers

All abstracts will be refereed. A criterion of acceptance will be originality. A condition of submission is that, if accepted, the paper will be presented at ISMTII 2005 by the author or one of the co-authors.

It is the responsibility of the author to submit a paper written to an acceptable level of English. If the author is unsure a native English speaker should review the paper prior to submission.

Abstracts submitted using the internet site will be acknowledged with an electronic receipt including an abstract reference number, which should be quoted in all correspondence. Otherwise acknowledgement will be made by post.